

**Search Notes**

Application/Control No.

10/773,640

Examiner

Syed Zaidi

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	466	12/28/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
AST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12/28/2007	SZ
Inventor :CHEN ET AL.	12/28/2007	SZ
IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	12/28/2007	SZ
(370/466 370/465 370/464 370/280 370/281 370/298).CCLS.	12/28/2007	SZ
Consulted with SPE Seema S. Rao	12/28/2007	SZ